IN THE CLAIMS

1.-73. Canceled

- (Original) An integrated circuit device having a film obtainable by chemical 74. vapor deposition of an organometallic compound of the formula $(R^1)_m M(PR^2_3)_x$, where M is a metal selected from the group consisting of manganese, technetium, rhenium, iron, ruthenium, osmium, cobalt, rhodium, iridium, nickel, palladium, and platinum wherein (a) when M is manganese, technetium or rhenium, m is 1, x is 5 and m+x is 6; (b) when M is iron, ruthenium or osmium, m is 0, 1, 2, 3 or 4; x is 2, 3, 4 or 5 and m + x is 4, 5, 6 or 7; (c) when M is cobalt, rhodium or iridium, m is 1, 2, 3 or 4 and x is 2, 3 or 4 and m + x is 4, 5, 6, 7 or 8; and (d) when M is nickel, palladium or platinum, m is 0 or 2, x is 2, 3, or 4 and m + x is 2, 3, 4, 5 or 6; each R^1 is independently selected from the group consisting of hydrogen, deuterium, N2, H2, D2 and a group of the formula -CR32-CR32-R4; each R2 is independently selected from the group consisting of lower alkyl, aryl, arylalkyl, alkoxy, aryloxy, arylalkoxy, alkylsilyl, arylsilyl, arylalkylsilyl, alkoxysilyl, aryloxysilyl, arylalkoxysilyl, alkylsiloxy, arylsiloxy, arylalkylsiloxy, alkoxysiloxy, aryloxysiloxy, arylalkoxysiloxy, alkylsilylalkyl, arylsilylalkyl, arylalkysilylalkyl, alkoxysilylalkyl, aryloxysilylalkyl, arylalkoxysilylalkyl, alkylsiloxyalkyl, arylsiloxyalkyl, arylalkylsiloxyalkyl, alkoxysiloxyalkyl, aryloxysiloxyalkyl, arylalkoxysiloxyalkyl, alkylsilylalkoxy, arylsilylalkoxy, arylalkylsilylalkoxy, alkoxysilylalkoxy, aryloxysilylalkoxy arylalkyloxysilylalkoxy, alkylsiloxyalkoxy, arylsiloxyalkoxy, arylalkylsiloxyalkoxy, alkoxysiloxyalkoxy, aryloxysiloxyalkoxy, and arylalkoxysiloxyalkoxy; each R3 is independently selected from the group consisting of hydrogen, deuterium, C1-C6 alkyl, C1-C6 cycloalkyl, phenyl, benzyl, (C1-C2 alkyl or alkoxy)3-silyl, and (C1-C2 alkyl or alkoxy)3-siloxy and wherein at least two groups R3 are selected from the group consisting of hydrogen and deuterium; R4 is hydrogen or deuterium; and wherein when M is cobalt and one group R¹ is selected to be N₂, then m is 2 and the second group R¹ is hydrogen or deuterium.
 - 75. (Original) The integrated circuit device of claim 74 wherein M is cobalt.

76. (Original) A method for forming a powder containing a metal or metal derivative comprising:

providing a medium; and

dispersing a vapor or liquid into the medium, the vapor or liquid containing an organometallic compound of the formula (R¹)_mM(PR²₃)_x, where M is a metal selected from a Group VIIb, VIII, IX or X metal wherein (a) when M is manganese, technetium or rhenium, m is 1, x is 5 and m+x is 6; (b) when M is iron, ruthenium or osmium, m is 0, 1, 2, 3 or 4; x is 2, 3, 4 or 5 and m + x is 4, 5, 6 or 7; (c) when M is cobalt, rhodium or iridium, m is 1, 2, 3 or 4 and x is 2, 3 or 4 and m + x is 4, 5, 6, 7 or 8; and (d) when M is nickel, palladium or platinum, m is 0 or 2, x is 2, 3 or 4 and m + x is 2, 3, 4, 5 or 6; each R^1 is independently selected from the group consisting of hydrogen, deuterium, N2, H2, D2 and a group of the formula -CR32-CR32-R4; each R² is independently selected from the group consisting of lower alkyl, aryl, arylalkyl, alkoxy, aryloxy, arylalkoxy, alkylsilyl, arylsilyl, arylalkylsilyl, alkoxysilyl, aryloxysilyl, arylalkoxysilyl, alkylsiloxy, arylsiloxy, arylalkylsiloxy, alkoxysiloxy, aryloxysiloxy, arylalkoxysiloxy, alkylsilylalkyl, arylsilylalkyl, arylalkysilylalkyl, alkoxysilylalkyl, aryloxysilylalkyl, arylalkoxysilylalkyl, alkylsiloxyalkyl, arylsiloxyalkyl, arylalkylsiloxyalkyl, alkoxysiloxyalkyl, aryloxysiloxyalkyl, arylalkoxysiloxyalkyl, alkylsilylalkoxy, arylsilylalkoxy, arylalkylsilylalkoxy, alkoxysilylalkoxy, aryloxysilylalkoxy arylalkyloxysilylalkoxy, alkylsiloxyalkoxy, arvlsiloxyalkoxy, arylalkylsiloxyalkoxy, alkoxysiloxyalkoxy, aryloxysiloxyalkoxy, and arylalkoxysiloxyalkoxy; each R³ is independently selected from the group consisting of hydrogen, deuterium, C₁-C₆ alkyl, C₁-C₆ cycloalkyl, phenyl, benzyl, (C₁-C₂ alkyl or alkoxy)₃silyl, and (C1-C2 alkyl or alkoxy)3-siloxy and wherein at least two groups R3 are selected from the group consisting of hydrogen and deuterium, R4 is hydrogen or deuterium; and wherein when M is cobalt and one group R¹ is selected to be N₂, then m is 2 and the second group R¹ is hydrogen or deuterium.

- 77. (Original) The method of claim 76 wherein the medium is at a temperature at or above the thermal decomposition temperature of the organometallic precursor compound.
 - 78. (New) The integrated circuit device of claim 74 wherein M is manganese.

- 79. (New) The integrated circuit device of claim 74 wherein M is technetium.
- 80. (New) The integrated circuit device of claim 74 wherein M is rhenium.
- 81. (New) The integrated circuit device of claim 74 wherein M is iron.
- 82. (New) The integrated circuit device of claim 74 wherein M is ruthenium.
- 83. (New) The integrated circuit device of claim 74 wherein M is osmium.
- 84. (New) The integrated circuit device of claim 74 wherein M is rhodium.
- 85. (New) The integrated circuit device of claim 74 wherein M is iridium.
- 86. (New) The integrated circuit device of claim 74 wherein M is nickel.
- 87. (New) The integrated circuit device of claim 74 wherein M is palladium.
- 88. (New) The integrated circuit device of claim 74 wherein M is platinum.